# From Atoms to Bits

## Ahmet Onat 2018

onat@sabanciuniv.edu

## **Layout of the Lecture**

- Analog interfacing to sensors:
  - Signal conditioning
  - Sampling and quantization
  - Bridge circuits and instrumentation amplifiers
- Linearization
- Design for low power
- Digital interfacing to sensors

## **Desirable Sensor Characteristics**

- Sensor reading equal to the measured quantity
- Suitable
  - accuracy, precision,
  - range, sensitivity  $\rightarrow$  gain
  - resolution, etc.
- Low noise
- Linearity

## **Characteristics of Instrumentation**

- Accuracy: How close is the measurement to measured.
- Precision: What is the uncertainty in the measurement.
- Range: Which value interval is measurable?
- Sensitivity: For a given change in input, the amount of the change in output.
- Resolution: Smallest amount of measurable change
- Repeatability: Under the same conditions, can we get the same measurement?

### **Accuracy - Precision**

How accuracy and precision are related?



- Inaccurate but precise?
  - Metal ruler on a hot day: Same precision bad accuracy

## **Sensitivity - Range**

- Generally high sensitivity sounds good.
- However, high sensitivity restricts range.
- Deliberately  $\rightarrow$  nonlinear sensor can be used.



- 1mV precision;
  - 8bit: 0.256V range
  - 12bit: 4.096V

## **Analog Interfacing to Sensors**

There are 3 main stages in sensing:

- Physics
- Electronics
- Information
- $\rightarrow$  Pysics will not be treated.



# Signal Conditioning Electronics

## **Signal Conditioning System**

- 1. Sensor Output
- 2. Preamplifier stage
- 3. Removal of offset
- 4. Antialiasing filter
- 5. Amplifier



## **Signal Conditioning: Sensor**

- 1. Sensor
- Low power electrical signal  $\rightarrow \begin{cases} Low voltage \\ Low current \end{cases}$
- Wide frequency bandwidth
  - Aliasing during sampling
- Offset voltage
  - Prevents use of full quantizer range



## **Signal Conditioning: Sensor**

#### 1. Sensor

- Voltage source with impedance
- $P_{o max} \rightarrow r_o = r_i$  OR
- $r_i \rightarrow \infty : V_s = X_s$

(Calculate like a voltage divider)





## **Signal Conditioning: Preamplifier**

#### 2. <u>Preamplifier stage</u>

- Extract largest amount of power from signal or,
- Draw the least amount of current.
- Matched impedance circuit
- Low noise
- High gain



## **Signal Conditioning: Preamplifier**

Draw the least amount of current:

Voltage follower configuration



Susceptibility to ESD increases.



## **Signal Conditioning: Offset Removal**

Offset

remove

Xp

Xo

Antialiasing

Filter

#### 3. Offset remove

Physical

Quantity

Sensor

 The information content is confined to a small part of the signal range.

Pre-

amplifier

 Amplification will not allow max precision of the quantizer: 2 MSB always set: 11xxxxx 12 bit ADC → 10bit ADC Information content
No information

Amplifier

## **Signal Conditioning: Offset Removal**

- 3. Offset remove
- Difference amplifier.

$$V_{o} = \frac{R_{f}}{R_{1}} (V_{p} - V_{off})$$



 ${\ensuremath{\,{\rm \bullet}\,}} V_{\rm off}$  : Constant offset voltage for removal.



## **Signal Conditioning: Filter**

#### 4. Antialiasing Filter

- "A bandlimited function is completely determined by its samples taken at more than twice the maximum frequency component"
- It is necessary to limit the bandwidth of the signal for:
  - Sampling
  - Noise suppression



## **Signal Conditioning: Filter**

- Filter characteristic:
  - Passband ripple must be less than ADC resolution.
  - Bandwidth limit frequency at 2<sup>-N</sup> gain.

Pre-

amplifier

What order filter?

Sensor

Physical

Quantity



## **Signal Conditioning: Amplifier**

#### 5. Amplification

- Signal is amplified to the reference voltage of the ADC.  $x_a(t) < x_{max} = V_{ref}$ 





## **Signal Conditioning: Amplifier**

- Simple non-inverting amplifier circuit.
- Ideal gain (A≈∞): <sup>V</sup><sub>o</sub>/<sub>V<sub>i</sub></sub> = (1+ <sup>R<sub>f</sub></sup>/<sub>R<sub>1</sub></sub>)

   Actual gain: <sup>V</sup><sub>o</sub>/<sub>V<sub>i</sub></sub> = A(R<sub>1</sub>+R<sub>f</sub>)/AR<sub>1</sub>+R<sub>1</sub>+R<sub>f</sub>



• Error for  $A=50,000, R_1=1k\Omega, R_2=9k\Omega, V_i=0.500V$ :

$$V_{o \infty} = 5.000 V$$
  
 $V_{o 50 k} = 4.998 V$   $e = 2000 \mu V$   
For 5V, 12bit:  $\Delta = 1221 \mu V$ 

#### **Data Converter**

6. Sample and Hold

#### 7. Quantizer



## **Sample and Hold**

- Ideal sampling requires
  - zero duration and
  - infinite currents.



 The body resistance of the transistor V<sub>a</sub> turns the S&H into a low pass filter.





Actual sample and hold



Sample and hold equivalent circuit

## Sample and Hold

- Time constant of a 1<sup>st</sup> order RC filter:
- $\tau = RC s$
- It is necessary to keep sampling for at least 5τ to allow the capacitor to be charged to V<sub>a</sub>
- Microcontrollers allow the adjustment of the charging period.
- Higher precision ADC requires longer charge times: "Acquisition Time"
- It is not possible to exceed  $f = \frac{1}{5}\tau$  for sampling.

## Sample and Hold

- Sampling several signals at the same instant.
- Several ADC can be used.
- More commonly, synchronous sampling, sequential conversion:
- In specialized applications several ADC are used: Motor current sampling, lab measurement etc.



## **Sampling of Continuous Time Signals**

 The Fourier transform of a continuous time signal is given by:

$$X(f) = \int_{-\infty}^{\infty} x(t) e^{-2\pi f t} dt$$
  

$$X_{s}(f) = \sum_{k=-\infty}^{\infty} X(f + kf_{s})$$
  

$$X_{s}(f) = \sum_{k=-\infty}^{\infty} X(f + kf_{s})$$

• When a signal is sampled by  $f_s$ , its frequency spectrum becomes periodic by  $f_s$ .

## **Sampling of Continuous Time Signals**



With correct filtering, original signal can be exactly recovered.

## **Sampling of Continuous Time Signals**

However, if low sampling frequency is used:



Source of figures: Wikipedia.org

### **The Data Converter AKA Quantizer**

Analog to digital conversion (ADC) is a search operation.

$$x_{q} = \left[ 2^{N} \frac{V_{\text{in}}}{V_{ref}} + \frac{\Delta}{2} \right]$$
$$\Delta = V_{ref} / 2^{N}$$



- Precision is limited to finite value,
- Information about input is lost.
- Time consuming OR complex operation.



#### **The Data Converter AKA Quantizer**

Ideal, normalized, 3 bit quantizer.



Source of figures: D.H. Sheingold, Analog Digital Conversion Handbook, 1986

### **Quantization Error as Linear Noise**

- V<sub>in</sub> is ambiguous →
- Quantization can be modeled as additive noise.

 $x_q = V_{\text{in}} + n_q$ 



## **Quantization Error as Linear Noise**

- Vin is not known  $\rightarrow$
- Quantization can be modeled as additive noise.

$$x_q = V_{\text{in}} + n_q$$

 $SNR_{dB} = 6.02N + 1.76$ 

 $(V_{in} = Asin(\omega t), N bit quantizer)$ 



## **Quantizer Performance**



 Each can be corrected in software (not easily)

Source of figures: D.H. Sheingold, Analog Digital Conversion Handbook, 1986

## **Quantizer Realizations: Flash**

- Low latency
- High complexity O(2<sup>N</sup>)
- Bad linearity



## **Quantizer Realizations: Successive Approx.**

- Higher latency.
- Low complexity.
- Good linearity.



Source of figures: D.H. Sheingold, Analog Digital Conversion Handbook, 1986

# **Digital Signal Processing**

### **From Physical Quantity to Physical Value**

The final stage is digital signal processing.



### **Oversampling / Noise Shaping**

- Signal is sampled at much higher rate than Shannon.
- After ADC, DSP low pass filter is applied.
- Low order anti-aliasing filter is sufficient.
- Increase in precision is obtained due to averaging.


# **Oversampling / Noise Shaping**

- Sampling rate is much higher than required by Shannon theorem.
- Quantization noise power is constant, regardless of sampling rate.
- Signal spectrum amplitude is inreased proportionally.  $V_a(f)' = V_a(f) \times OSR$
- Signal occupies less of the digital bandwith.  $f'_{max} = f_{max}/OSR$



#### **Oversampling / Noise Shaping**

 Downsampling by OSR brings the signal back to desired band.



## **Oversampling / Noise Shaping**

- Oversampling increases the ADC precision.
- OSR=  $4^{w} \rightarrow w$  bit increase in quantizer precision.
- For 4 bit increase:  $OSR=4^4=256$  times oversampling.
- 44.1KSPS  $\rightarrow$  11.3MSPS is too much!
- Oversampling can be augmented with noise shaping to improve ratio.

## **Oversampling with Noise Shaping**

- Quantization noise is injected during ADC.
- The fedback system causes the quantization noise spectrum to be
  - low at low frequencies.
  - Higher at high frequencies.



## **Oversampling with Noise Shaping**

- The feedback loop has different gains for
  - quantization noise and
  - Signal.
- Quantization noise is concentrated towards higer frequencies.
- OSD=8 is sufficient for 4 bit increase
  vs. OSD=256



# **High Precision Applications**

#### **Reference Voltage**

- Changes in  $V_{ref}$  have the same effect as changing the input voltage.
- Compensation for:
  - Temperature
  - Manufacturing tolerances

$$x_q = \left[ 2^N \frac{V_{\text{in}}}{V_{ref}} + \frac{\Delta}{2} \right], \quad \Delta = V_{ref}/2^N$$



#### **Reference Voltage Tolerance**

- LM336A-2.5: 2.5V reference diode.
- 2.44 ~ 2.54*V* at 25°.

• 8 bit ADC, 
$$V_{in} = 1V$$
: 
$$\begin{cases} V_{ref} = 2.44 V \rightarrow x_q = 100 \\ V_{ref} = 2.54 V \rightarrow x_q = 104 \end{cases}$$

- How to calibrate?  $ADJ \rightarrow K$   $ADJ \rightarrow K$  Vret minLM336A

ADC reading

#### **Reference Voltage Tolerance**

Calibration of reference voltage tolerance

- 1. Multiply by correction coefficient in software
  - Firmware in each device must be different.
  - In 8 bit processors, correction multiplication is difficult.
- 2. Electrical adjustment:
  - Manual labor
  - Long term drift
  - Temperature dependence of VR



## **Common Ground Problems**

- Microprocessor with daughterboard for temperature sensor.
- GND shared between
  - Daughterboard electronics
  - Sensor voltage



#### **Common Ground**

- Connection cables have  $1\Omega$  resistance.
- Daughterboard draws 50mA current.
- ADC reads 20% more: 300mV



#### **Common Ground**

- Connection cables have  $1\Omega$  resistance.
- Daughterboard draws 50mA current.
- Ground of the sensor is separated.
- Single ground distribution point.



# **Secondary Sensors**

#### **Secondary Sensors**

- Electrical component values may change in response to a change in a physical variable.
- Change is small; 0.1% or less.
- Straightforward measurement of value:
  - May have large offset error.
  - May depend on other variables (temperature etc.)
  - Require high precision.



#### **Sensor Bridges**

- Balanced bridge circuits.
- Output voltage derived from resistor divider.

$$V_{o} = V_{b} \frac{R_{1}}{R_{1} + R_{4}} - V_{b} \frac{R_{2}}{R_{2} + R_{3}}$$
  
For  $\frac{R_{1}}{R_{4}} = \frac{R_{2}}{R_{3}} \rightarrow V_{o} = 0V$ 



• No bias.  $\rightarrow$  Large gain can be used.

#### **Types of Bridge Circuits**

- Bridge may consist of 1, 2, 4 elements.
- Larger elements have better sensitivity.
- $V_o$  depends on  $V_b \rightarrow$  Stable supply.
- Measurement load must be zero.



#### **Example Use of Bridge**

- Strain gage measures bending strain.
- $R_1$  and  $R_2$  change in opposite directions.
- Stretch measurement eliminated.



## **Amplifiers for Sensor Bridges**

- Instrumentation amplifier is used.
- High input impedance
- High CMRR
- Gain is set by external resistor Rg.
- Many good chips exist AD620 etc.

$$V_{o} = (V_{i+} - V_{i-})R_{1} \left(\frac{1 + R_{1}}{R_{g}}\right) \left(\frac{R_{3}}{R_{2}}\right)$$



# Linearization, Calibration

# **Sensor Commissioning**

- The sensor output is generally not:
  - Linear
  - Calibrated
- Determine inverse function to obtain physical value from the readings.
- Calibrate the sensor to increase the accuracy of the readings.



Sharp GP2Y0A41SK0F Reflective distance sensor. Distance vs output voltage

## Linearization

- Sensor linear offset and gain correction
- Calibration measurements:  $\begin{cases} a_1 = mp_1 + b \\ a_2 = mp_2 + b \end{cases}$



 Periodic calibrations may be needed: Use electronic switch to connect reference.

#### Lookup Table - Worst Case

- Extreme nonlinearities.
- Wasteful of memory.
  16bit → 32bit: 262kB ROM.

STM32F405RGT6: 1MB ROM STM8s103F: 8kB ROM

 If multiple sensors must be fused, even larger footprint.

ADC	Physical
0	234
1	200
2	192
3	216
1022	48
1023	132

#### **Piecewise Linearization**

- In a certain range of readings, use a specific linearization.
- Smaller memory footprint
- More run-time computation
- Worse error



Physical value

In Range	Slope	Offset
a1~a2	m1	b1
a2~a3	m2	b2
a3~a4	m3	b3
a4~a5	m4	b4

# **Curve Fitting**

- With several sensors, curve fitting can be performed.  $p = c_{10} + c_{11}a_1 + c_{12}a_2 + \dots + c_{21}a_1^2 + c_{22}a_2^2 + c_{23}a_1a_2 + \dots$
- Coefficients:
  - Calculated before shipment
  - By operator, using calibrated measurement samples
  - Automatic, periodic calibrations

# Low power Sensing

## **Low Power Sensing**

- Power reduction through low duty cycle.
- "Intelligent" sensor with power modes.
- Sensor powered down when not needed.
- Whole system powered down most of the time.



\*OFF mode can be entered from any state by removing the power

Source of figure: NXP, "Low-Power Sensing" White Paper.

# **Low Duty Cycle Operation**

- Most processors have sleep timers.
  - Processor consumes power during sleep
  - I/O pins used to power down sensors may keep consuming power.
- Many power management chips are on the market.



TI TPL5110 System timer

# **Low Duty Cycle Operation**

- Processor sets sleep time
- Timer turns off power: Whole system is switched off.
- Processor sleep mode: 1µA
- Timer sleep mode: 35nA



#### **Energy Harvesting**

- Solar cells, piezo devices, thermoelectric generators etc.
- Maximum power must be derived from the generator.  $P = V \times I$
- Stored in a battery.



# **Solar Cell Basics**

- Efficiency.
  - 8%~45%. General commercial: ~15%
  - Solar Flux: 1kW/m<sup>2</sup> noontime.
  - ~150W/m<sup>2</sup>.
- Power output.
  - More current draw, less voltage.

 $P = V \times I$ 

- Track the best V~I ratio. (!)
- Power conversion.
  - Change voltage as required.
  - $\rightarrow$  buck/boost converter- regulator.



# **Solar Cell Sizing**

- Determine
  - power consumption  $(V_{cc}, I_c)$
  - duty ratio (seconds/hr): V<sub>cc</sub> x I<sub>c</sub> x s

→ Energy requirement

- Size the battery: 3.7V, 0.5Ah etc.
- Size the solar cell:
  - Use the peak sun hour of deployment location.
  - Budget
  - Safety margin
    - $\rightarrow$  Area of the solar cell required.

# **FLOPs per Watt**

- Processor clock can be actively throttled.
- Low clock speed:
  - Low power consumption
  - Long active time
- High clock speed:
  - High power consumption
  - Short active time
- Most suitable FLOPS/W depends on mode, active peripherals etc.



#### **Koomey's Law**

 "...the power needed to perform a task requiring a fixed number of computations will fall by half every 1.5 years,"

J.Koomey, S.Berard et al, "Implications of Historical Trends in the Electrical Efficiency of Computing", IEEE Annals Hist. Comp, V33-3, pp. 46~54, 2011



# **Integrated Sensors**

# **High Precision Applications**

- MP5611 barometric pressure sensor. (MEAS Switzerland)
- Accurate to 1ft of absolute altitude.
- 24bit ADC (△≈200nV)
- Discrete implementation requires expensive signal conditioning circuits.



#### FUNCTIONAL BLOCK DIAGRAM



#### **Integrated Sensors**

- High precision applications require great engineering and calibration effort.
- Many sensors are offered in:
  - Sensor +
  - Signal conditioning +
  - Power management +
  - Subsystem control packages
- End user connects the sensor over "I<sup>2</sup>C, "SPI" "CAN" etc.
# (Some) References

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## **Contact Information**

Ahmet Onat

- Sabanci University, Istanbul, Turkey
- Mail: onat@sabanciuniv.edu
- Web: http://people.sabanciuniv.edu/onat

# **Research projects**

- I am carrying out projects in
  - Reinforcemet learning for dynamic systems
  - Networked real-time systems. Internet of Things IoT
  - Haptic interfaces for 3D displays
  - Linear motor design
  - Underwater autonomous robots
- See:

http://people.sabanciuniv.edu/onat

Enthusiastic students are welcome to help!

#### **Linear motor elevators**

- Vertical linear motor design
- Project funded by Fujitec, Japan
- 2007-2013
- 450kg payload, 1000m length
- Prototype, patents, publications
- Magnetic, electronic, control, safety design



## **Dihedral Corner Reflector Array (DCRA)**

- A passive optical device
- That can create real reflections to form floating images in the air
- Haptic feedback for projected solid objects







#### **SWARMS**

Modeling of underwarter autonomous vehicles (IoT)



#### **Networked control systems**

- A novel method for control over networks with unpredictable delay & data loss
- Stability analysis, simulation & prototype
- Tolerant of large amounts of delay
- Also wireless Ethernet application
- Publications & prototype control systems





# Laboratory work

Will be programming:

- ARM prcessor using 'C' language
- Blink lights,
- Move servos,
- Communication,
- Real-Time OS...

